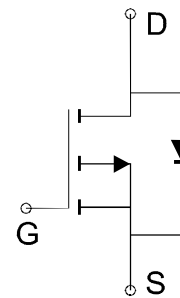
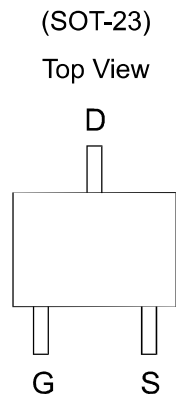


**P-Channel Enhancement Mode Mosfet**

**GENERAL DESCRIPTION**

The ME2309 is the P-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching and low in-line power loss are needed in a very small outline surface mount package.

**PIN CONFIGURATION**



**FEATURES**

- $R_{DS(ON)} \leq 215m\Omega @ V_{GS} = -10V$
- $R_{DS(ON)} \leq 260m\Omega @ V_{GS} = -4.5V$
- Super high density cell design for extremely low  $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

**APPLICATIONS**

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch
- DSC
- LCD Display inverter

Ordering Information: ME2309(Pb-free)

ME2309-G (Green product-Halogen free)

**Absolute Maximum Ratings (TA=25°C Unless Otherwise Noted)**

Parameter	Symbol	Maximum Ratings	Unit	
Drain-Source Voltage	$V_{DS}$	-60	V	
Gate-Source Voltage	$V_{GS}$	±20	V	
Continuous Drain	$T_A = 25^\circ C$	$I_D$	-1.9	A
	$T_A = 70^\circ C$	$I_D$	-1.5	A
Pulsed Drain Current	$I_{DM}$	-7.6	A	
Maximum Power Dissipation	$T_A = 25^\circ C$	$P_D$	1.4	W
	$T_A = 70^\circ C$	$P_D$	0.9	W
Storage Temperature Range	$T_{stg}$	-55 to 150	°C	
Thermal Resistance-Junction to Ambient*	$R_{\theta JA}$	90	°C/W	

\*The device mounted on 1in<sup>2</sup> FR4 board with 2 oz copper

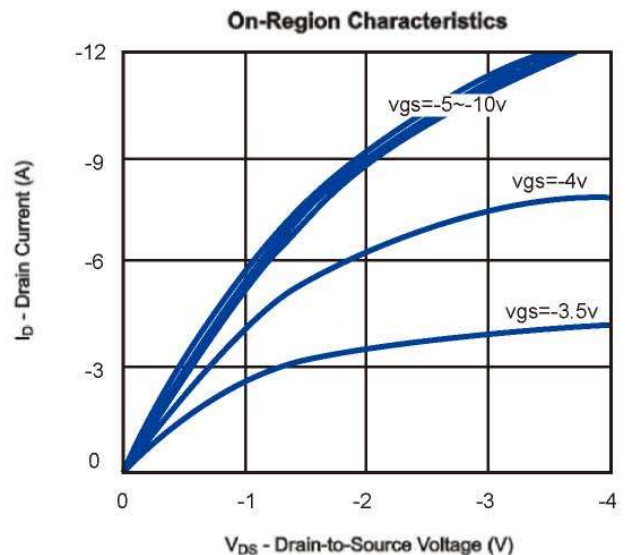
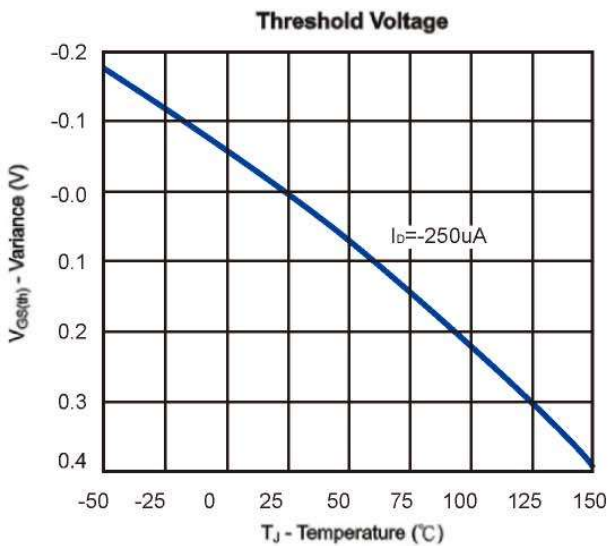
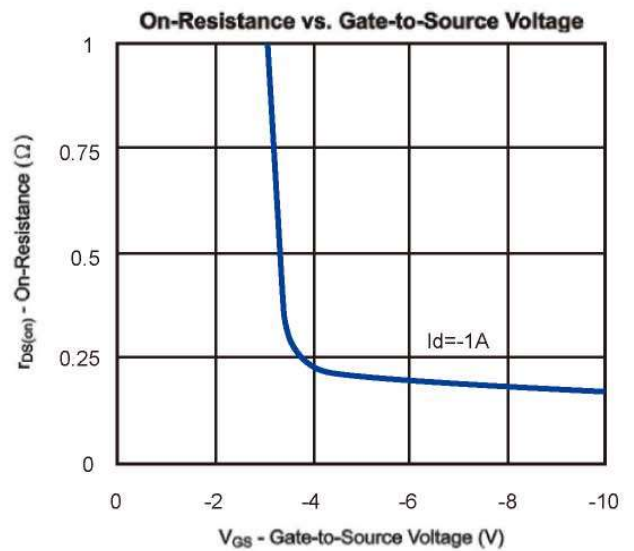
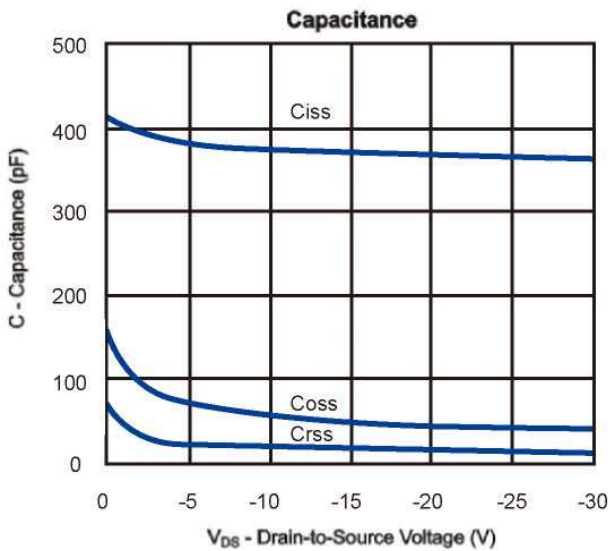
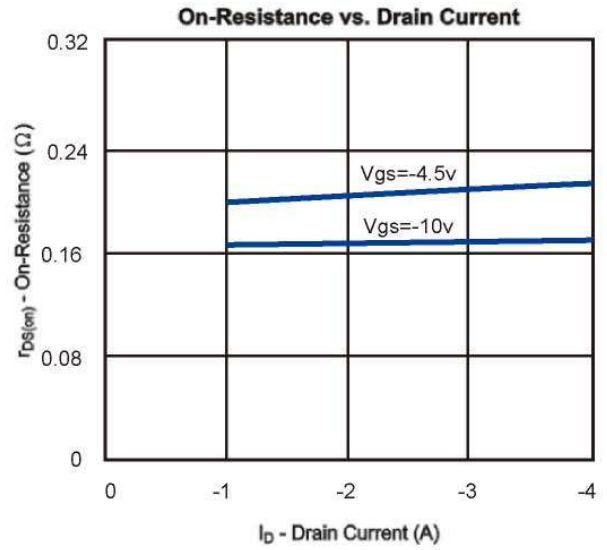
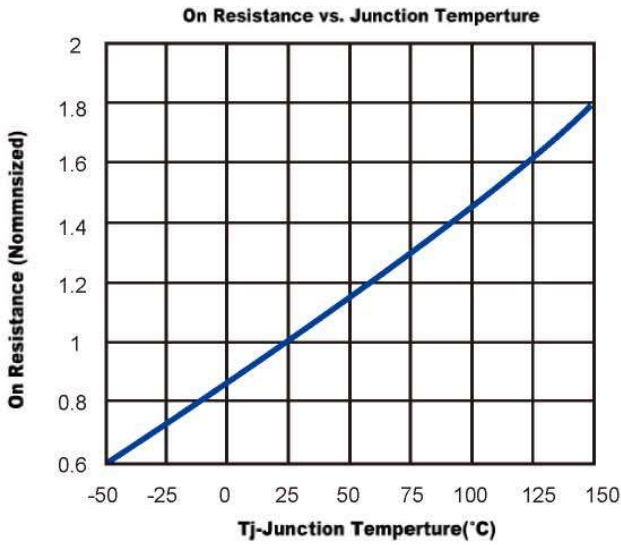
**P-Channel Enhancement Mode Mosfet**
**Electrical Characteristics** ( $T_A=25^{\circ}\text{C}$  Unless Otherwise Specified)

Symbol	Parameter	Limit	Min	Typ	Max	Unit
<b>STATIC</b>						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\ \mu A$	-60			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\ \mu A$	-1		-3	V
$I_{GSS}$	Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$			$\pm 100$	nA
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-60V, V_{GS}=0V$			-10	$\mu A$
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS}=-10V, I_D=-1.8A$		170	215	m $\Omega$
		$V_{GS}=-4.5V, I_D=-1.4A$		200	260	
$V_{SD}$	Diode Forward Voltage	$I_S=-1.2A, V_{GS}=0V$			-1.2	V
<b>DYNAMIC</b>						
$Q_g$	Total Gate Charge	$V_{DS}=-48, V_{GS}=-4.5V, I_D=-1A$		6.3		nC
$Q_{gs}$	Gate-Source Charge			2.3		
$Q_{gd}$	Gate-Drain Charge			1.8		
$C_{iss}$	Input Capacitance	$V_{DS}=-25V, V_{GS}=0V,$ $f=1MHz$		364		pF
$C_{oss}$	Output Capacitance			41		
$C_{rss}$	Reverse Transfer Capacitance			12		
$R_g$	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$		9.8		$\Omega$
$t_{d(on)}$	Turn-On Delay Time	$V_{DS}=-30V, R_L=30\ \Omega$ $R_{GEN}=3.3\ \Omega, V_{GS}=-10V$ $I_D=-1A$		20		ns
$t_r$	Turn-On Rise Time			33.1		
$t_{d(off)}$	Turn-Off Delay Time			5.2		
$t_f$	Turn-Off Fall Time			3.8		

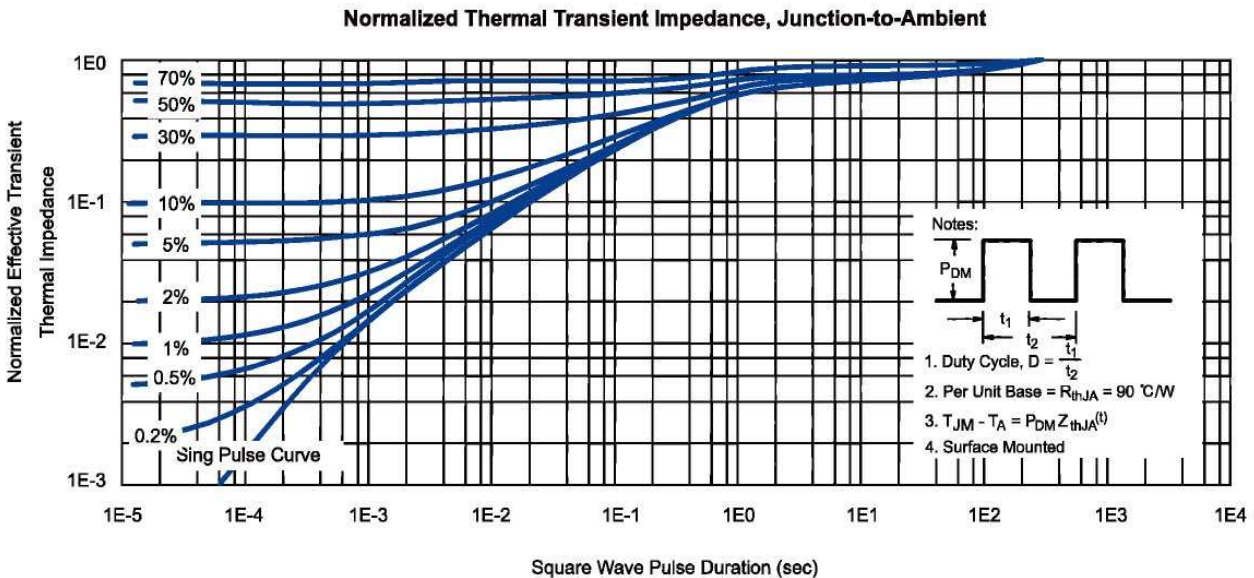
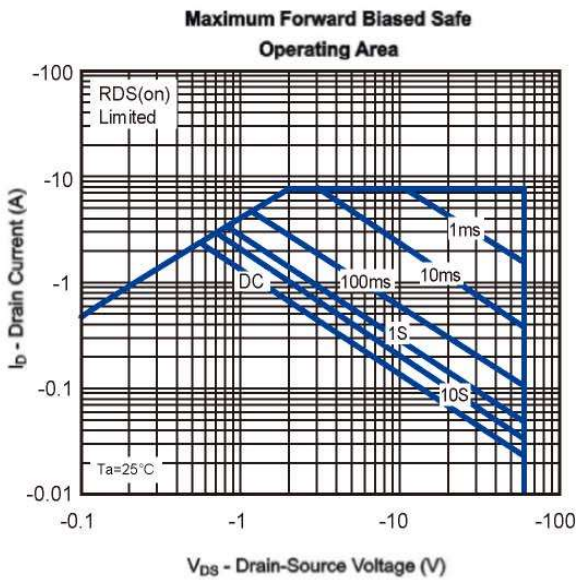
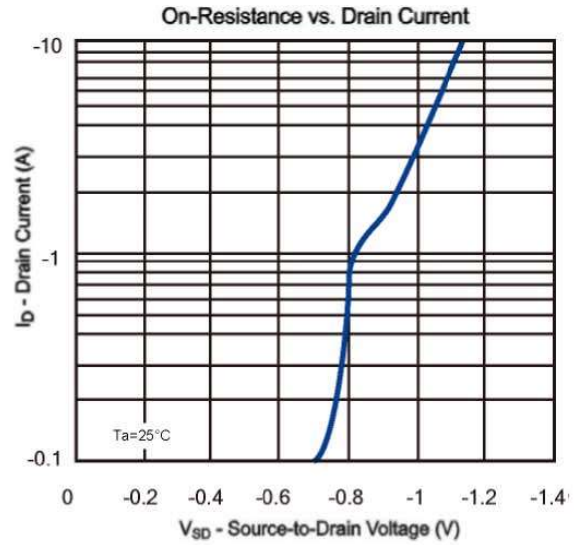
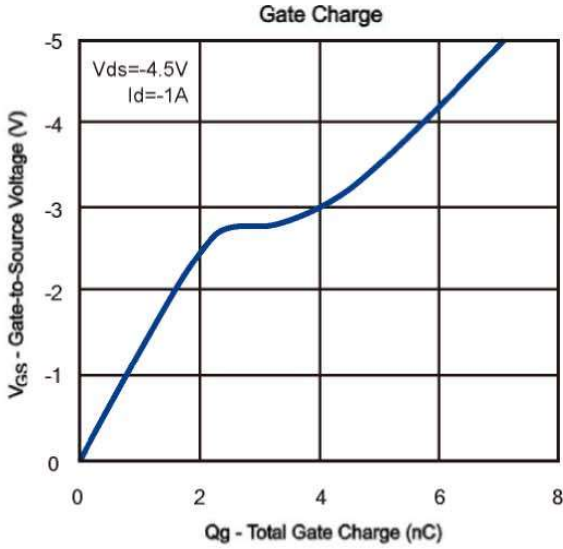
 Notes: a. Pulse test; pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$ 

b. Matsuki Electric/ Force mos reserves the right to improve product design, functions and reliability without notice.

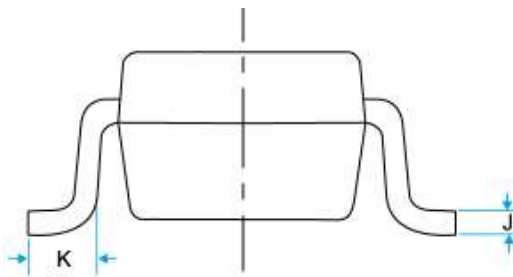
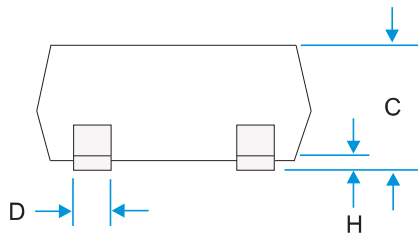
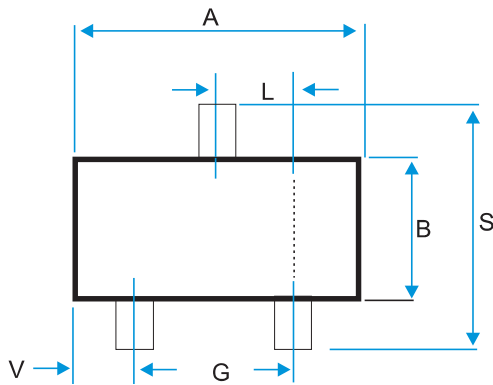
**P-Channel Enhancement Mode Mosfet**  
**Typical Characteristics (T<sub>J</sub> =25°C Noted)**



**P-Channel Enhancement Mode Mosfet**  
**Typical Characteristics (T<sub>J</sub> = 25°C Noted)**



**SOT-23 Package Outline**



DIM	MILLIMETERS (mm)	
	MIN	MAX
A	2.800	3.00
B	1.200	1.70
C	0.900	1.30
D	0.350	0.50
G	1.780	2.04
H	0.010	0.15
J	0.085	0.20
K	0.300	0.65
L	0.890	1.02
S	2.100	3.00
V	0.450	0.60